PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Docket No: A8612

Pranav ASHAR, et al.

Appln. No.: Cont. of Serial No. 09/425,886

Confirmation No.: Not Yet Assigned Group Art Unit: Not Yet Assigned

Filed: June 24, 2003 Examiner: Not Yet Assigned

For: FAST ERROR DIAGNOSIS FOR COMBINATIONAL VERIFICATION

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §§ 1.97 and 1.98

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure under 37 CFR §1.56, Applicant hereby notifies the U.S. Patent and Trademark Office of the documents which are listed on the attached PTO/SB/08 A & B (modified) form which are all the references of record in parent application No. 09/425,886. Applicant is not submitting duplicate copies of these references but requests that they be listed on the face of any patent granted on the above application. (See 37 CFR §1.98(d)). Copies of any cited copending applications, if not previously submitted, are being submitted herewith.

The submission of the listed documents is not intended as an admission that any such document constitutes prior art against the claims of the present application. Applicant does not waive any right to take any action that would be appropriate to antedate or otherwise remove any listed document as a competent reference against the claims of the present application.

INFORMATION DISCLOSURE STATEMENT Cont. of Serial No. 09/425,886 Docket No. A8612

Respectfully submitted,

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WASHINGTON OFFICE

PATENT TRADEMARK OFFICE

Date: June 24, 2003

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^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Complete if Known Substitute for Form 1449 A & B/PTO **Application Number** Cont. of Serial No. 09/425,886 INFORMATION DISCLOSURE Confirmation Number Not Yet Assigned June 24, 2003 Filing Date STATEMENT BY APPLICANT First Named Inventor Pranav ASHAR et al. Art Unit Not Yet Assigned (use as many sheets as necessary) Examiner Name Not Yet Assigned Sheet Attorney Docket Number A8612

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